

ESD9L5.0L1

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Surface Mount Uni-Directional TVS For ESD Protection Diode with Ultra Low Capacitance: 5.0V

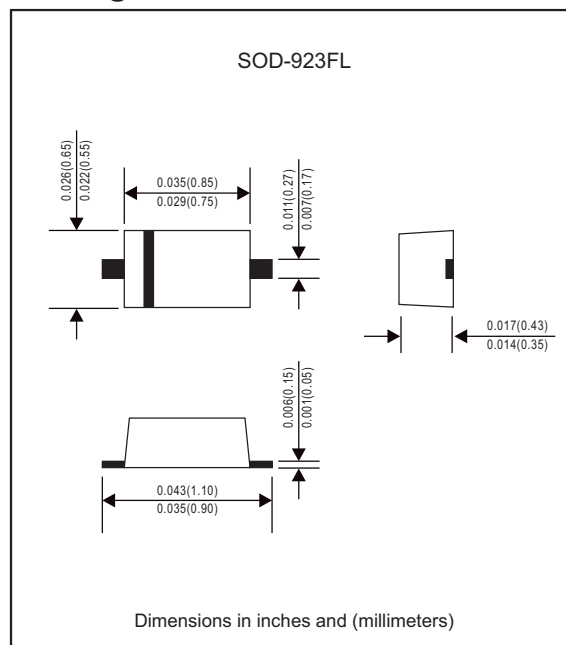
Features

- Ultra low capacitance 0.5 pF (typ.)
- Low clamping voltage
- Stand-off voltage: 5 V
- Low leakage
- Response time is typically <1.0 ns
- Provide transient protection:
IEC 61000-4-2 (ESD) $\pm 25\text{KV}$ (Air) / $\pm 20\text{KV}$ (Contact)
IEC 61000-4-4 (EFT) 40A (5/50ns)
- This is a Pb-Free device
- Suffix "-H" indicates halogen-free part, ex. ESD9L5.0L1-H

Mechanical data

- Epoxy : UL94-V0 rated flame retardant
- Case : Molded plastic, SOD-923FL
- Terminals : Plated terminals, solderable per MIL-STD-750, Method 2026
- Polarity : Indicated by cathode band
- Mounting Position : Any
- Weight : Approximated 0.00044 gram

Package outline



Maximum ratings (at $T_A=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Value	Unit
Peak Pulse Power (According to IEC 61000-4-5)	P _{PP}	10	W
Peak Pulse Current (According to IEC 61000-4-5)	I _{PP}	1	A
ESD per IEC 61000-4-2 (Air) ESD per IEC 61000-4-2 (Contact)	ESD	± 25 ± 20	KV
Operating junction temperature range	T _J	-55 to +125	°C
Storage temperature range	T _{STG}	-55 to +150	°C

Electrical characteristics (at $T_A=25^\circ\text{C}$ unless otherwise noted)

Parameter	Condition	Symbol	Min.	Typ.	Max.	Unit
Reverse Stand-Off Voltage		V _{RWM}			5	V
Reverse Breakdown Voltage	I _T =1mA	V _{BR}	6.0	8.0	9.0	V
Reverse Leakage Current	V _{RWM} =5V	I _R		0.1	1.0	uA
Clamping Voltage (Note 1)	I _{PP} =1.0A, T _P =8/20us	V _C			10	V
Junction Capacitance	Between I/O Pin and GND, V _R =0V, f=1MHz	C _J		0.5	0.8	pF

Note:

1. Non-repetitive current pulse 8/20 us exponential decay waveform according to IEC 61000-4-5.

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Fig.1 VOLTAGE SWEEPING OF I/O TO GND

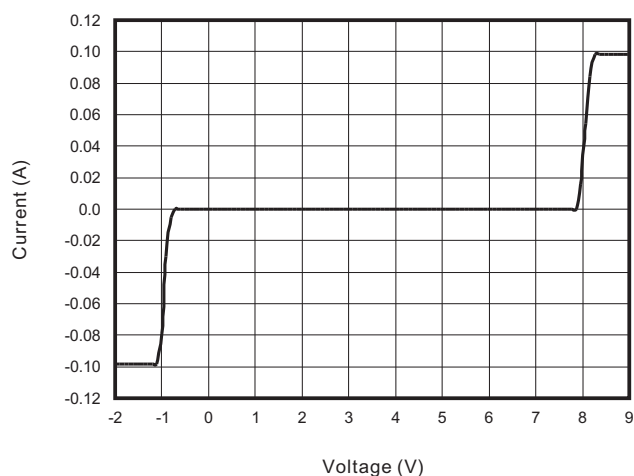
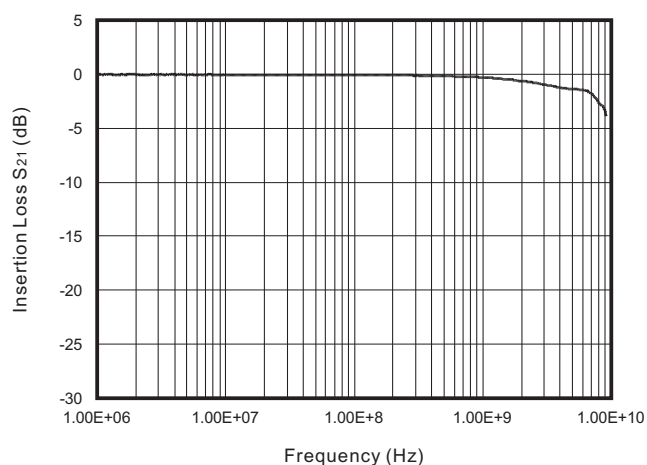
Fig.2 INSERTION LOSS S₂₁ of I/O to GND

Fig.3 CAPACITANCE VS. REVERSE VOLTAGE

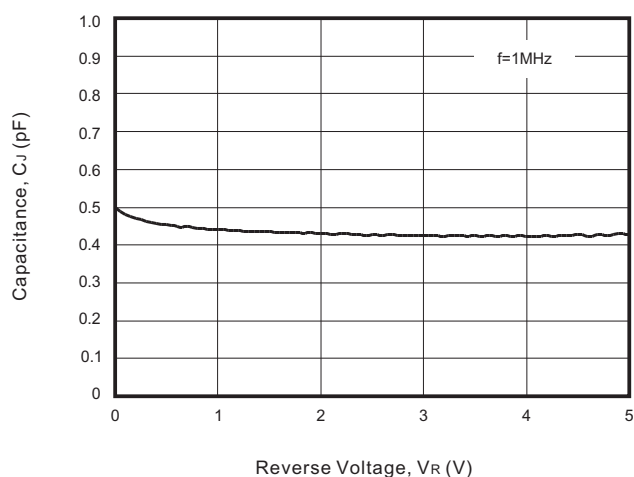
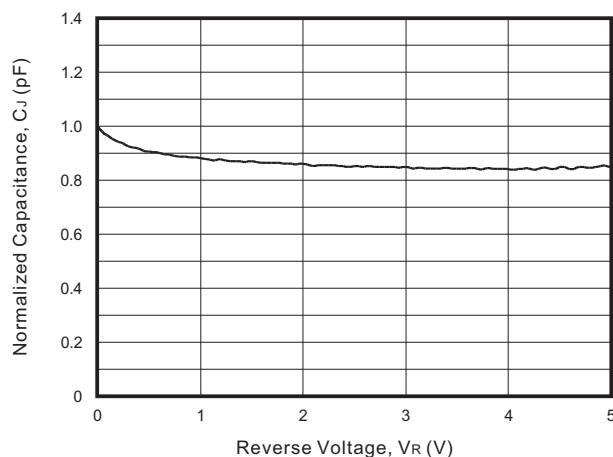
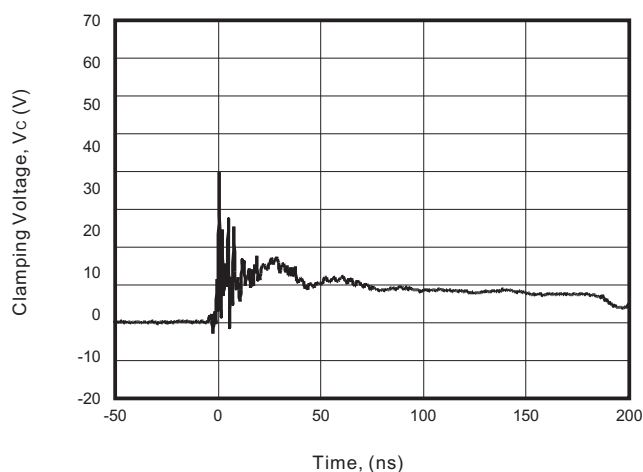
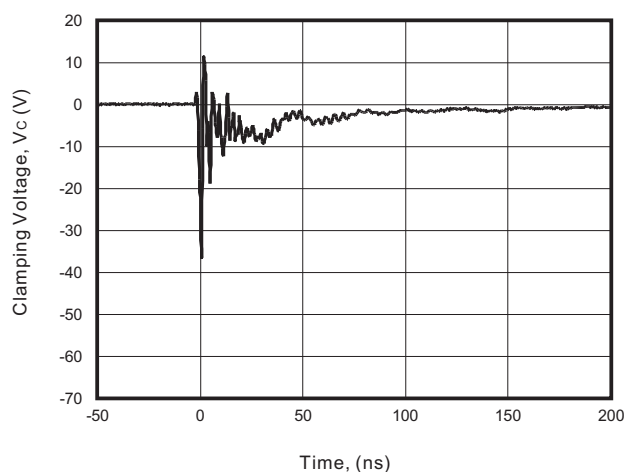


Fig.4 NORMALIZED CAPACITANCE VS. REVERSE VOLTAGE

Fig.5 ESD CLAMPING OF I/O TO GND
(+8KV CONTACT PER IEC 61000-4-2)Fig.6 ESD CLAMPING OF I/O TO GND
(-8KV CONTACT PER IEC 61000-4-2)

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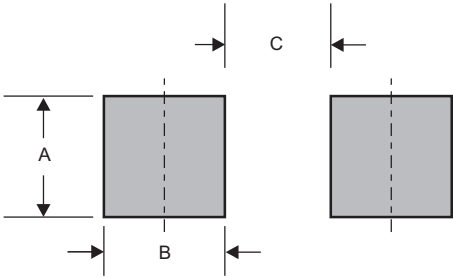
Pinning information

Pin	Simplified outline	Symbol
Pin1 cathode Pin2 anode		

Marking

Type number	Marking code
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Suggested solder pad layout

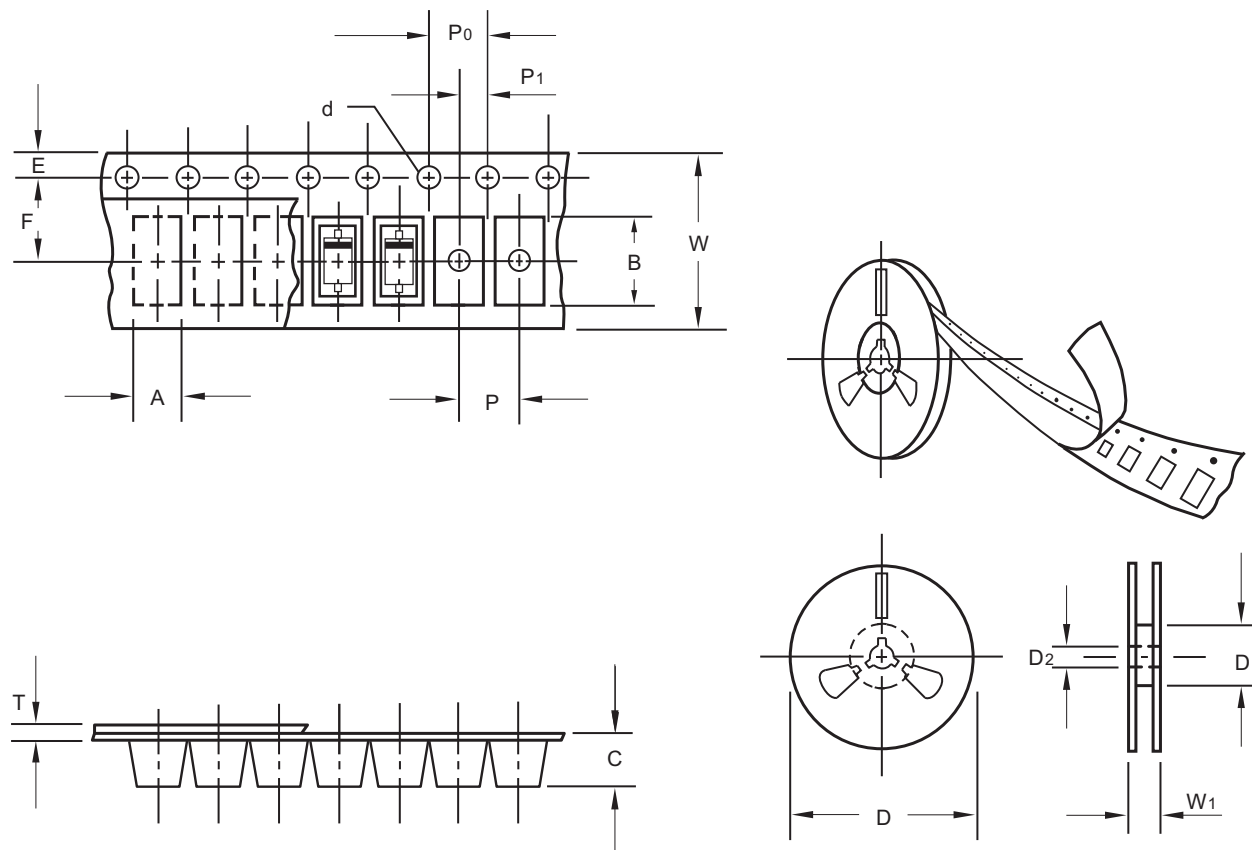


Dimensions in inches and (millimeters)

PACKAGE	A	B	C
SOD-923FL	0.016 (0.40)	0.012 (0.30)	0.024 (0.60)

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Packing information



unit:mm

Item	Symbol	Tolerance	SOD-923FL
Carrier width	A	0.05	0.67
Carrier length	B	0.05	1.12
Carrier depth	C	0.05	0.52
Sprocket hole	d	0.1	1.50
13" Reel outside diameter	D	2.0	-
13" Reel inner diameter	D ₁	min	-
7" Reel outside diameter	D	2.0	178.00
7" Reel inner diameter	D ₁	min	62.00
Feed hole diameter	D ₂	0.5	13.00
Sprocket hole position	E	0.1	1.75
Punch hole position	F	0.1	3.50
Punch hole pitch	P	0.1	2.00
Sprocket hole pitch	P ₀	0.1	4.00
Embossment center	P ₁	0.1	2.00
Overall tape thickness	T	0.1	0.20
Tape width	W	0.3	8.00
Reel width	W ₁	1.0	11.40

Note: Devices are packed in accordance with EIA standard RS-481-A and specifications listed above.

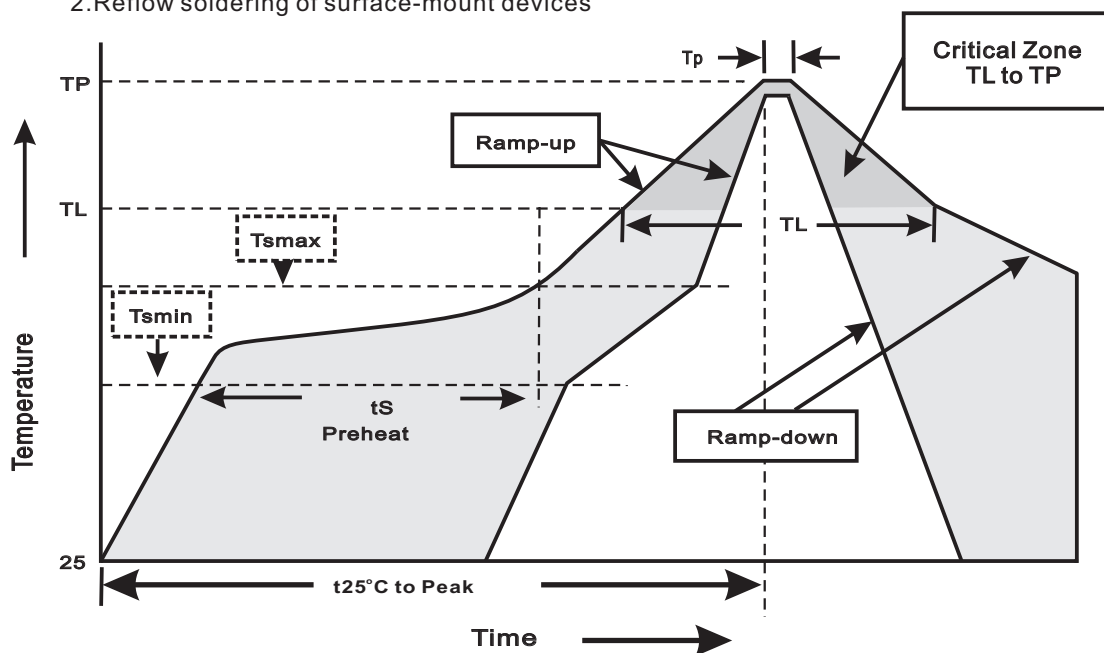
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Reel packing

PACKAGE	REEL SIZE	REEL (pcs)	COMPONENT SPACING (m/m)	BOX (pcs)	INNER BOX (m/m)	REEL DIA, (m/m)	CARTON SIZE (m/m)	CARTON (pcs)	APPROX. GROSS WEIGHT (kg)
SOD-923FL	7"	10,000	2.0	100,000	183*123*183	178	382*257*387	800,000	11.2

Suggested thermal profiles for soldering processes

- 1.Storage environment: Temperature=5°C~40°C Humidity=55%±25%
- 2.Reflow soldering of surface-mount devices



3.Reflow soldering

Profile Feature	Soldering Condition
Average ramp-up rate(T _L to T _P)	<3°C/sec
Preheat -Temperature Min(T _{smmin}) -Temperature Max(T _{smmax}) -Time(min to max)(t _s)	150°C 200°C 60~120sec
T _{smmax} to T _L -Ramp-upRate	<3°C/sec
Time maintained above: -Temperature(T _L) -Time(t _L)	217°C 60~260sec
Peak Temperature(T _P)	255°C-0/+5°C
Time within 5°C of actual Peak Temperature(t _P)	10~30sec
Ramp-down Rate	<6°C/sec
Time 25°C to Peak Temperature	<6minutes

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High reliability test capabilities

Item Test	Conditions	Reference
1. Solder Resistance	at $260\pm5^{\circ}\text{C}$ for $10\pm2\text{sec.}$ immerse body into solder $1/16''\pm1/32''$	MIL-STD-750D METHOD-2031
2. Solderability	at $245\pm5^{\circ}\text{C}$ for 5 sec.	MIL-STD-202F METHOD-208
3. High Temperature Reverse Bias	$V_{BR} = V_{BR \text{ Min}} * 80\%$ at $T_J = 125^{\circ}\text{C}$ for 168 hrs.	MIL-STD-750D METHOD-1038
4. Pressure Cooker	$15P_{SIG}$ at $T_A = 121^{\circ}\text{C}$ for 4 hrs.	JESD22-A102
5. Temperature Cycling	-55°C to $+125^{\circ}\text{C}$ dwelled for 30 min. and transferred for 5min. total 10 cycles.	MIL-STD-750D METHOD-1051
6. Humidity	at $T_A = 85^{\circ}\text{C}$, RH=85% for 1000hrs.	MIL-STD-750D METHOD-1021
7. High Temperature Storage Life	at 175°C for 1000 hrs.	MIL-STD-750D METHOD-1031